GBFULL (United Kingdom (GB) Patents Full-Text)

Subject Coverage

All patent-relevant areas of science and technology, i.e., all classes of the International Patent Classification

File Type

Full-Text

Features

Thesauri	International Patent Classification (/IPC), Cooperative Patent Classification (/CPC), European Patent Classification (/EPC and /ICO)		
Alerts (SDIs)	Weekly or monthly (weekly is the default)		
CAS Registry Numbers® Identifiers	☐	SLART	☑
Keep & Share	☑	Structures	☐
Register Links	☑		

Record Content

- Full-text of patent applications and patent specifications published in the United Kingdom from 1782 onwards.
- Patent applications begin in 1982, when the British Intellectual Property Office started to publish applications.
- Database records comprise all documents published for one application. Records of the database contain bibliographic data, including patent applicant and inventor information, patent, application and priority application data, IPC, CPC (including CPC combination sets), and EPC classification codes, plus the searchable text of the complete documents, comprising titles, abstracts, description and claims.
- Numeric values of 59 physical and chemical properties are searchable in about 20,000 variants of the base and additional units within all full-text fields in English.
- Ultimate Owners are searchable in the field /UO and /UOS.
- Standardized and normalized patent assignee names are searched in /PAS and /PAN.
- Key terms, indexed and displayed in the field /KT, enhance retrieval of relevant results, and make the evaluation of results more efficient. They are useful to broaden search scope more precisely than Basic Index searches.
- Database records comprise all documents published for one application.
- Clipped images (mostly front-page images) are also included, when available.
- Some of the full-text has been created by Optical Character Recognition (OCR) software. Therefore, characters may be misinterpreted, or portions of the text may be incomplete.

File Size

- More than 3 million family records with more than 3.9 million publications (09/2024)
- More than 2 million front page images from 1893 to present (09/2024)

Coverage

Comprehensive 1893 to present, first document from 1782

Updates

Weekly

Language

English

Database Producer

LexisNexis Business Information Solutions B.V.
Radarweg 29
1043 NX Amsterdam
The Netherlands

Sources	Patent applications and granted patents published by the United Kingdom Intellectual Property Office
User Aids	• Online Helps (HELP DIRECTORY lists all help messages available) • STNGUIDE
Clusters	• AEROTECH • ALLBIB • AUTHORS • CORPSOURCE • ENGINEERING • FULLTEXT • HPATENTS • NPS • PATENTS • PNTTEXT STN Database Cluster information

Search and Display Field Codes

If multiple search terms are linked with an AND-operator, all terms are searched in the complete database record, i.e., in all publications referring to one application. For a search in a specific publication of the record, connect the search term and the patent kind code with the (L)-proximity operator, e.g.,
S BOREHOLE/AB,TI,CLM (L) GBA/PK limits the search to British applications GBA.

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TIEN), abstract (ABEN), detailed description (DETDEN), claims (CLMEN), and main claims (MCLMEN), and key terms (KT) fields)	None or /BI	S TRANSISTOR AND ELECTRODE S ACOUSTIC SENSOR S ?TRANSFER?	TIEN, ABEN, DETDEN, CLMEN, MCLMEN, KT
Abstract*	/ABEN (or /AB)	S BOREHOLE/ABEN	ABEN
Accession Number	/AN	S 2403388/AN	AN
Application Country (WIPO code and text)	/AC	S GB/AC	AI
Application Date **(1)**	/AD	S AD=JAN 2003	AI
Application Kind Code	/AK	S GBA/AK	AI
Application Number **(2)**	/AP	S GB2000-10050/AP	AI
Application Number Original	/APO	S GB1817326/APO	APO
Application Year **(1)**	/AY	S AY>=2000	AI
Claims*	/CLMEN (or /CLM)	S DERIVATION/CLMEN	CLMEN
Cooperative Patent Classification **(3)**	/CPC	S C12N0009-1085/CPC	CPC
Cooperative Patent Classification, Action Date	/CPC.ACD	S 20121113/CPC.ACD	CPC.TAB
Cooperative Patent Classification, Keywords	/CPC.KW	S C12N0009-1085/CPC (S) I/CPC.KW	CPC.TAB
Cooperative Patent Classification, Version	/CPC.VER	S 20130101/CPC.VER	CPC.TAB
Data Entry Date **(1)**	/DED	S 20181206/DED	DED
Data Update Date **(1)**	/DUPD	S 20181207/DUPD	DUPD
Detailed Description *	/DETDEN (or /DETD)	S ?DERIVATION/DETDEN	DETDEN
Document Type	/DT (or /TC)	S PATENT/DT	DT
Entry Date **(1)**	/ED	S 20240715/ED	ED
Entry Date Full-text **(1)**	/EDTX	S 20181211/EDTX	EDTX
EPC, Keyword Terms	/EPC.KW	S B2A/EPC.KW	EPC
European Patent Classification **(3)**	/EPC (or /ECLA, /EPCLA)	S A01B0001-02B/EPC	EPC
Field Availability	/FA	S ABEN/FA	FA
ICO (in-computer-only) Classification **(3)**	/ICO	S M07D0333/ICO	ICO
ICO Keyword Terms	/ICO.KW	S ADD/ICO.KW	ICO
IdT (Indeling der Techniek)	/IDT	S B21K0001-56/IDT	IDT
International Patent Classification (ICM, ICS, IPCI, IPCR) **(3)**	/IPC	S A01B001/IPC	ICM, ICS, IPCI, IPCR
International Patent Classification (ICM, ICS)	/IC (or /IPCMS)	S A24B/IC	IC, ICM, ICS
Inventor	/IN (or /AU)	S MANDEL WALTER/IN S MANDEL?/IN	IN
Inventor, Country (WIPO code and text)	/IN.CNY	S FR/IN.CNY	IN, IN.CNY
IPC, Action Date **(1)**	/IPC.ACD	S 20051008/IPC.ACD	IPC.TAB
IPC, Keyword Terms	/IPC.KW	S INITIAL/IPC.KW	IPC.TAB
IPC, Reform	/IPC.REF	S A01B0001-16/IPC.REF	IPC.TAB
IPC, Version	/IPC.VER	S 7/IPC.VER	IPC.TAB
IPC Additional	/ICA (or /IPCA)	S A61K0007-00/ICA	ICA
IPC Initial	/ICI (or /IPCIN)	S A61K0007-06/ICI	ICI

General Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
IPC Initial	/IPCI	S B21B0001/IPCI	IPCI
IPC Main	/ICM	S A01N001/ICM	ICM
IPC Reclassified	/IPCR	S B21B0001-34/IPCR	IPCR
IPC Secondary	/ICS	S A01B0013-00/ICS	ICS
Key Terms*	/KT	S BIOAVAILABILITY PARAMETER/KT	KT
Language (code and text)	/LA	S EN/LA	LA
Language of Filing (code and text)	/LAF	S ENGLISH/LAF	LAF
Main Claim*	/MCLMEN (or /MCLM)	S ?FRACTURE?/MCLM	MCLMEN
Number of Claims **(1)**	/CLMN	S 5-7/CLMN	CLMN
Number of Paragraphs in DETD (Detailed Description) **(1)**	/DETN	S DETN<10	DETN
Patent Assignee **(4)**	/PA (or /CS)	S BASF AG/PA	PA
Patent Assignee, Country (WIPO code and text)	/PA.CNY	S DE/PA.CNY	PA.CNY
Patent Assignee, Total	/PA.T	S UNIVERSITY NEVADA/PA.T	PA.T
Patent Assignee Normalized **(4)**	/PAN	S BASF AG/PAN	PAN
Patent Assignee Standardized **(4)**	/PAS	S BASF AG/PAS	PAS
Patent Country	/PC	S GB/PC	PI
Patent Information Type	/PIT	S "GBA PATENT SPECIFICATION (UNDER NO. 2000000) OR PUBLISHED PATENT APPLICATION (FROM NO. 2000000)"/PIT	PIT
Patent Kind Code	/PK	S GBA/PK	PI
Patent Number **(2)**	/PN (or /PATS)	S GB2003005/PN	PI
Patent Number Original	/PNO	S GB201301786/PNO	PNO
Patent Number/Kind Code	/PNK	S GB2000003 A/PNK	PI
Physical Properties	/PHP	S VOLT/PHP (S) TOUCH SCREEN/BI	KWIC
Priority Country (WIPO code and text)	/PRC	S AU/PRC S AUSTRALIA/PRC	PRN, PRAI
Priority Date **(1)**	/PRD	S PRD=APRIL 2 2003 S 20030402/PRD	PRN, PRAI
Priority Date First **(1)**	/PRDF	S 20000109/PRDF	PRN, PRAI
Priority Number Kind Code	/PRK	S DEA/PRK	PRN, PRAI
Priority Number **(2)**	/PRN	S DE2000-10001525/PRN	PRN, PRAI
Priority Number Original	/PRNO	S EP12001001/PRNO	PRNO, PRAO
Priority Year **(1)**	/PRY	S 1993/PRY	PRN, PRAI
Priority Year First **(1)**	/PRYF	S 1993-1994/PRYF	PRN, PRAI
Publication Date **(1)**	/PD	S PD=JAN-FEB 2003	PI
Publication Year **(1)**	/PY	S PY>2003 AND L1	PI
Related Application Country	/RLC	S WO/RLC	RLI
Related Application Date **(1)**	/RLD	S 20170203/RLD	RLI
Related Application Number	/RLN	S WO 2017-CA24/RLN	RLI
Related Application Type	/RLT	S PCT APPLICATION/RLT	RLI
Related Application Year **(1)**	/RLY	S 2017/RLY	RLI
Related Patent Country	/RLPC	S WO/RLPC	RLPI
Related Patent Date **(1)**	/RLPD	S 20000309/RLPD	RLPI
Related Patent Number	/RLPN	S WO2000000008/RLPN	RLPI
Related Patent Year **(1)**	/RLPY	S 2005/RLPY	RLPI
Title*	/TIEN (or /TI)	S FLUID###/TIEN	TIEN
Ultimate Owner **(4)**	/UO	S BASF/UO	UO
Ultimate Owner Standardized **(4)**	/UOS	S BASF/UOS	UOS
Update Date **(1)**	/UP	S JUN 2024/UP	UP
Update Date Full-Text **(1)**	/UPTX	S 20240503/UPTX	UPTX

(1) Numeric search field that may be searched using numeric operators or ranges.
(2) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
(3) An online thesaurus is available in this field.
(4) Search with implied (S) proximity is available in this field.

Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group	/APPS	AP, APO, PRN, PRNO, RLN	S GB2010-10008/APPS	AI, APO, PRAI, PRAO, APPS
Patent Assignee Group	/PASS	PA, PAN, PAS, PA.T, UO, UOS	S BIONTECH/PASS	PA, PAN, PAS, PA.T, UO, UOS
Patent Number Group	/PATS	PN, PNO, RLPN	S GB2009000005/PATS	PI, PNO, RLPI

Property Fields (1)

In GBFULL a numeric search for a specific set of physical properties (/PHP) is available within the full-text fields (TIEN, ABEN, DETDEN, CLMEN, BI). The numeric values are not displayed as single fields but are instead highlighted within the hit displays.

Use EXPAND/PHP to search for all available physical properties. A search with the respective field codes will be carried out in all database fields with English text. The /PHP index contains a complete list of codes and related text for all physical properties available for numeric search.

Field Code	Property	Unit	Symbol	Search Examples
/AOS	Amount of substance	Mol	mol	S 10 /AOS
/BIR	Bit Rate	Bit/Second	bit/s	S 8000-10000/BIR
/BIT	Stored Information	Bit	Bit	S BIT > 3 MEGABIT
/CAP	Capacitance	Farad	F	S 1-10 MF/CAP
/CATA	Catalytic Activity	Katal	kat	S 1-10/CATA
/CDN	Current Density	Ampere/Square Meter	A/m^2	S CDN>10 A/M**2
/CMOL	Molarity, Molar Concentration	Mol/Liter	mol/L	S UREA/BI (S) 8/CMOL
/CON	Conductance	Siemens	S	S 1S-3/CON
/DB	Decibel	Decibel	dB	S DB>50
/DEG	Degree	Degree	°	S CYLINDER/BI (S) 45/DEG
/DEN (/C)	Density (Mass Concentration	Kilogram/Cubic Meter	kg/m^3	S 5E-3-10E-3/DEN
/DEQ	Dose Equivalent	Sievert	Sv	S 100/DEQ
/DOA	Dosage	Milligram/Kilogram/Day	mg/kg/day	S 100-300/DOA
/DOS (/LD50)	Dose	Milligram/Kilogram	mg/kg	S DOS>0.8
/DV	Viscosity, dynamic	Pascal * Second	Pa*s	S DV>5000
/ECH (/CHA)	Electric Charge	Coulomb	C	S 0.0001-0.001/ECH
/ECO (/ECND)	Electrical Conductivity	Siemens/Meter	S/m	S ECO>800 S/M (15A) AQUEOUS
/ELC (/ECC)	Electric Current	Ampere	A	S 1-10/ELC
/ELF (/ECF)	Electric Field	Volt/Meter	V/m	S 200/ELF
/ENE	Energy	Joule	J	S DROPLETS (10A) 40 JOULE - 70 JOULE /ENE
/ERE (/ERES)	Electrical Resistivity	Ohm*Meter	Ohm*m	S ERE>0.1
/FOR	Force	Newton	N	S 50 N /FOR
/FRE (/F)	Frequency	Hertz	Hz	S OSCILLAT?/BI (S) 1- 3/FRE

Property Fields (1) (cont'd)

Field Code	Property	Unit	Symbol	Search Examples
/IU	International Unit	none	IU	S IU>1000 (P) VITAMIN A
/KV	Viscosity, kinematic	Square Meter/Second	m2/s	S METHYLPOLYSILOXANES/BI (10A) 200-300 CST /KV
/LEN (/SIZ)	Length, Size	Meter	m	S 1-4/LEN
/LUME	Luminous Emittance, Illuminance	Lux	lx	S 10-50/LUME
/LUMF	Luminous Flux	Lumen	Lm	S LUMF>1000
/LUMI	Luminous Intensity	Candela	cd	S LUMI<4
/M	Mass	Kilogram	kg	S ALLOY/BI (30A) 1E-10-1E-5/M
/MCH	Mass to Charge Ratio	none	m/z	S MCH=1
/MFD (/MFS)	Magnetic Flux Density	Tesla	T	S MFD>102
/MFR (/MFL)	Mass Flow Rate	Kilogram/Second	kg/s	S MFR<0.1
/MFST	Magnetic Field Strength	Ampere/Meter	A/m	S 10-20/MFST
/MM (/MW, /MOM)	Molar Mass	Gram/Mol	g/mol	S 2000-3000 G/MOL/MM
/MOLS	Molality of Substance	Mol/Kilogram	mol/kg	S 01.-10 MOL/KG/MOLS
/MVR	Melt Volume Rate, Melt Flow Rate	none	g/10 min	S 3/MVR
/PER	Percent (Proportionality)	none	%	S POLYMER?/AB (5A) 4/PER
/PHV (/PH)	pH Value	pH	pH	S 7.4-7.6/PHV
/POW (/PW)	Power	Watt	W	S "HG-XE-?"/BI (S) 100-200 WATT/POW
/PPM	Parts per million	Ppm	ppm	S 100 PPM /PPM (10A) ADDITIVE/BI
/PRES (/P)	Pressure	Pascal	Pa	S (VACUUM (5A) DISTILL?)/BI (S) 1000-1100/PRES
/RAD	Radioactivity	Becquerel	Bq	S 10-20/RAD
/RES	Electrical Resistance	Ohm	Ohm	S SENSOR /BI (S) 10- 100/RES
/RI	Refractive Index	none		S 3-4/RI
/RSP	Rotational Speed	Revolution/Minute	rpm	S 2 RPM - 100 RPM /RSP (S) ENGINE/BI
/SAR	Area /Surface Area	Square Meter	m2	S PLATE/BI (S) 10 M**2 - 100 M**2 /SAR
/SOL (/SLB)	Solubility	Gram/100 gram	g/100g	S SOL>20 G/100G (5A) WATER
/SSAM	Specific Surface Area, Mass	Square Meter/ Kilogram	m2/kg	S 1-10/SSAM
/STSC	Surface Tension	Joule /Square Meter	J/m2	S 60 J/M**2/STSC
/TCO (/TCND)	Thermal Conductivity	Watt/Meter*Kelvin	W/m*K	S 1/TCO (S) HEAT?
/TEMP (/T)	Temperature	Kelvin	K	S 20-25/TEMP
/TEX	Tex	Gram/Kilometer	g/km	S 1-5/TEX
/TIM	Time	Second	s	S ?INCUB?/BI (10A) 50 S - 150 S /TIM
/VEL (/V)	Velocity	Meter per Second	m/s	S REDUC?/BI (S) 1E-3-5E-3/VEL
/VELA	Velocity, angular	Radian/Second	rad/s	S VELA>10
/VLR	Volumetric Flow Rate	Cubic Meter/Second	m3/s	S 1 M**3/S - 2 M**3/S /VLR (S) ABRASIVE
/VOL	Volume	Cubic Meter	m3	S 1E-8-2E-8/VOL.EX
/VOLT	Voltage	Volt	V	S TENSION/BI (10A) 5E-3 V <VOLT<7E-3 V

(1) Exponential format is recommended for the search of particularly high or low values, e.g., 1.8E+7 or 1.8E7 (for 18000000) or 9.2E-8 (for 0.000000092).

International Patent Classification (/IPC) Thesaurus

The IPC thesaurus is available in the /IPC search field. The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1–7, use the field code followed by the edition number, e.g., /IPC2, for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th , and 5th editions. All relationship codes can be used with both the EXPAND and SEARCH. commands.

Code	Content	Examples
ADVANCED (ADV)	Advanced codes for the core level IPC code	E A61K0006-02+ADVANCED/IPC
ALL	All associated terms including definitions	E C01C003-00+ALL/IPC
BRO (MAN)	Complete class	E C01C+BRO/IPC
BT	Broader term	E C01F001-00+BT/IPC
CORE (COR)	Core codes for the advanced level IPC code	E G08C0019-22+CORE/IPC
DEF (ED)	Complete definition of the code, level (core, advanced) and IPC manual edition	E C01F001-00+ED/IPC
HIE	Hierarchy terms (all broader and narrower terms)	E C01B003-00+HIE/IPC
INDEX	Complete title of the code	E C01F001-00+INDEX/IPC
KT	Keyword term	E CYANOGEN+KT/IPC
NEXT	All next codes within the same class	E C01C001-00+NEXT/IPC
NEXTn	Next n codes (n = 1,2 ...) within the same class	E C01C001-00+NEXT5/IPC
NT	Narrower terms	E C01C+NT/IPC
PREV	All previous codes within the same class	E C01C001-12+PREV/IPC
PREVn	Previous n codes (n = 1,2 ...) within the same class	E C01C001-12+PREV10/IPC
TI	Complete title (definition) including broader terms	E C01F001-00+TI/IPC

ECLA (/EPC) and ICO Thesauri

These thesauri are available in the /EPC search field (for ECLA codes) and /ICO search field (for 'in-computer-only' codes). All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL	All usually required terms including definitions	E C12M0001-34H2+ALL/EPC E L32B0310:00+ALL/ICO
AUTO **(1)**	Automatic relationship	E G01J003-443+AUTO/EPC
BT	Broader terms	E G01J0003-443+BT/EPC
DEF	Complete definition of the code and CPC edition	E SCRAPER BIASING MEANS+CODE/EPC
HIE	Hierarchy terms (all broader and narrower terms)	E B65G0045-16+DEF/EPC
KT	Keyword term	E A01B0001+HIE/EPC
MAX	All associated terms	E LASER+KT/EPC
NEXT	All next codes within the same class	E G01J0003-44B+MAX/EPC
NEXT(n)	Next n codes (n = 1,2 ...) within the same class	E A01B0001-24+NEXT/EPC
NT	Narrower terms	E A01B0001-24+NEXT3/EPC
PREV	All previous codes within the same class	E G05B0001-04+NT/EPC
PREV(n)	Previous n codes (n = 1,2 ...) within the same class	E G05B0019-418N1+PREV/EPC
TI	Complete title (definition) including broader terms	E G05B0001-03+TI/EPC

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

CPC Thesaurus

This thesaurus is available in the /CPC search field. All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL	All usually required terms including definitions	E C12M0001-005+ALL/CPC
AUTO **(1)**	Automatic relationship	E G01J003-443+AUTO/CPC
BT	Broader terms	E G01J0003-443+BT/CPC
DEF	Complete definition of the code and CPC edition	E B65G0045-16+DEF/CPC
HIE	Hierarchy terms (all broader and narrower terms)	E A01B0001+HIE/CPC
KT	Keyword term	E LASER+KT/CPC
MAX	All associated terms	E G01J0003-44+MAX/CPC
NEXT	All next codes within the same class	E A01B0001-24+NEXT/CPC
NEXT(n)	Next n codes (n = 1,2 ...) within the same class	E A01B0001-24+NEXT3/CPC
NT	Narrower terms	E G05B0001-04+NT/CPC
PREV	All previous codes within the same class	E G05B0019-00+PREV/CPC
PREV(n)	Previous n codes (n = 1,2 ...) within the same class	E G05B0019-00+PREV2/CPC
TI	Complete title (definition) including broader terms	E G05B0001-03+TI/CPC

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI AU. The fields are displayed or printed in the order requested.

The information of the latest publication is displayed by default. To display the content for all levels of the record you can combine all display fields and formats with the qualifier .M except FA, SCAN, and TRIAL. The default display format is STD.M, i.e., all publication levels of one family in the STD format.

For displaying a particular publication of a database record, you can simply add for certain display field the kind code to the appropriate display format, e.g., ALL.A1. Fields that allow this are indicated by a number (3). Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
ABEN (AB, ABS)	Abstract	D TI AB 1-5
AI (AP) **(1)**	Application Information	D AI
AN	Accession Number	D L3 AN
APO (AIO)	Application Number Original	D APO
CLMEN (CLM) **(3)**	Claims	D CLM
CLMN **(2)**	Number of Claims	D CLMN
CPC	Cooperative Patent Classification	D CPC
CPC.TAB	CPC, Tabular	D CPC.TAB
DED	Data Entry Date	D DED
DETDEN (DETD) **(3)**	Detailed Description	D DETD
DETN **(2)**	Number of Paragraphs in DETD	D DETN
DT (TC)	Document Type	D DT
DUPD	Data Update Date	D DUPD
ED	Entry Date	D ED
EDP	Entry Date Patent	D EDP
EDTX	Entry Date of Full-Text	D EDTX
EPC (ECLA, EPCLA)	European Patent Classification	D EPC
FA	Field Availability (for all publication levels)	D FA
GI	Graphic Image	D GI
IC	International Patent Classification (Version 1-7) (ICM, ICS, ICA, ICI)	D IC

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
ICA (IPCA)	IPC, Additional	D ICA
ICI	IPC Index	D ICI
ICM	IPC Main	D IC
ICO	ICO (in-computer-only) Classification	D ICO
ICS	IPC Secondary	D ICS
IDT	IDT Classification	D IDT
IN (AU)	Inventor	D IN
IN.CNY	Inventor, Country	D IN.CNY
IPC	International Patent Classification (Version 1-8) (IPCI, IPCR, ICM, ICS, ICA, ICI)	D IPC
IPC.REF	IPC, Reform	D IPC.REF
IPCI	IPC Initial	D IPCI
IPCR	IPC Reclassified	D IPCR
KT	Key Terms	D KT
LA	Language	D LA
LAF	Language of Filing	D LAF
MCLMEN (MCLM)	Main Claim	D MCLM
PA (CS)	Patent Assignee	D PA
PA.CNY	Patent Assignee, Country	D PA.CNY
PAN	Patent Assignee Normalized	D PAN
PAS	Patent Assignee Standardized	D PAS
PI (PN) **(1)**	Patent Information	D PI
PIT	Patent Information Type	D PIT
PNK	Patent Number/Kind Code	D PNK
PNO **(2)**	Patent Number Original	D PNO
PRAI (PRN) **(1,5)**	Priority Information	D PRN
PRAO (PRNO) **(2)**	Priority Information Original	D PRNO
RLI (RLN)	Related Application Information	D RLI
RLPI	Related Patent Information	D RLPI
TIEN (TI)	Title	D TIEN
UO	Ultimate Owner	D UO
UOS	Ultimate Owner Standardized	D UOS
UP	Update Date	D UP
UPTX	Update Date Full-Text	D UPTX
ALL **(1,3)**	AN, EDP, ED, EDTX, UP, DED, DUPD, TIEN, IN, PA, PAS, PAN, UO, UOS, LAF, LA, DT, PIT, PI, AI, RLPI, RLI, PRAI, IPC, CPC, EPC, ICO, IDT, ABEN, DETDEN, CLMEN, KT	D ALL
DALL **(1)**	ALL delimited for post processing	D DALL
IALL **(1,3)**	ALL indented with text labels	D IALL
ALLG **(1)**	ALL plus graphic image	D ALLG
IALLG **(1)**	IALL plus graphic image	D IALLG
APPS **(1)**	AI, RLI, RLPI, PRAI	D APPS
BIB **(1)**	AN, EDP, ED, EDTX, UP, DED, DUPD, TIEN, IN, PA, PAS, PAN, UO, UOS, LAF, LA, DT, PIT, PI, AI, RLPI, RLI, PRAI, IPC, CPC, EPC, ICO, IDT	D BIB
BIBG **(1)**	BIB plus graphic image	D BIBG
IBIB **(1)**	BIB indented with text labels	D IBIB
IBIBG **(1)**	IBIB plus graphic image	D IBIBG
BRIEF **(1)**	AN, EDP, ED, EDTX, UP, DED, DUPD, TIEN, IN, PA, PAS, PAN, UO, UOS, LAF, LA, DT, PIT, PI, AI, RLPI, RLI, PRAI, IPC, EPC, ICO, IDT, ABEN, MCLMEN, KT	D BRIEF
BRIEFG **(1,4)**	BRIEF plus graphic image	D BRIEFG
IBRIEF **(1)**	BRIEF indented with text labels	D IBRIEF
IBRIEFG **(1,4)**	BRIEFG indented with text labels	D IBRIEFG
CPC.TAB	CPC, CPC.KW, CPC.ACD, CPC.VER in tabular format	D CPC.TAB
IND	IPC (ICA, ICI, ICM, ICS, IPCI, IPCR), CPC, EPC, ICO, IDT	D IND
IPC	International Patent Classification (ICA, ICI, ICM, ICS, IPCI, IPCR)	D IPC
IPC.TAB	IPC, IPC.KW, IPC.ACD, IPC.VER, in tabular version	D IPC.TAB
MAX (ALL.M) **(1)**	AN, EDP, ED, EDTX, UP, DED, DUPD, TIEN, IN, PA, PAS, PAN, UO, UOS, LAF, LA, DT, PIT, PI, AI, RLPI, RLI, PRAI, IPC, CPC, EPC, ICO, IDT, ABEN, DETDEN, CLMEN, KT, FA for all levels of publication	D MAX

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
MAXG (ALLG.M) **(1)**	MAX, plus graphic image	D MAXG
IMAX (IALL.M) **(1)**	MAX, indented with text labels	D IMAX
IMAXG (IALLG.M) **(1)**	IMAX, plus graphic image	D IMAXG
PASS	PA, PAN, PAS, PA.T, UO, UOS	D PASS
PATS **(1)**	PI, PNO, RLPI	D PATS
SCAN **(4)**	TI (random display without answer numbers)	D SCAN
STD **(1)**	AN, EDP, ED, EDTX, UP, DED, DUPD, TIEN, IN, PA, PAS, PAN, UO, UOS, LAF, LA, DT, PIT, PI, AI, RLPI, RLI, PRAI, IPC, CPC, EPC, ICO, IDT (STD.M is default)	D STD
STDG **(1)**	STD, plus graphic image	D STDG
ISTD **(1)**	STD, indented with text labels	D ISTD
ISTDG **(1)**	ISTD, plus graphic image	D ISTDG
TRIAL (TRI, SAM, SAMPLE, FREE)	EDP, ED, EDTX, UP, DED, DUPD, TIEN, FA, DETN, CLMN	D TRIAL
TX	DETDEN, CLMEN	D TX
HIT	Hit term(s) and field(s)	D HIT
KWIC	Up to 50 words before and after hit term(s) (KeyWord-In-Context)	D KWIC
OCC	Number of occurrences of hit term(s) and field(s) in which they occur	D OCC

(1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
(2) Custom display only.
(3) You can combine this display field with the qualifier .PK (Patent Kind Code) to display the content for a certain publication level of a record, e.g., CLM.B2.
(4) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.
(5) If priority information is not available for a certain document, this information is taken from the application information of this document and marked with an asterisk (*).

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

You can combine all fields except FA with the qualifier .M to SELECT/ANALYZE the content of all publication levels.

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Accession Number	AN	Y	Y
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Information Group	APPS	Y	Y
Application Kind Code	AK	Y **(3)**	Y
Application Number	AP (AI)	Y **(2)**	Y
Application Number Original	APO	Y	Y
Application Year	AY	Y	Y
CPC Classification	CPC	Y	Y
Data Entry Date	DED	Y	Y
Data Update Date	DUPD	Y	Y
Document Type	DT (TC)	Y	Y
Entry Date	ED	Y	Y
Entry Date Full-Text	EDTX	Y	Y
Entry Date Patent	EDP	Y	Y
European Patent Classification	EPC (ECLA, EPCLA)	Y	N

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Field Availability	FA	Y	N
International Patent Classification	IC	Y	N
Inventor	IN (AU)	Y	Y
Inventor, Country	IN.CNY	Y	Y
ICO (in-computer-only) Classification	ICO	Y	Y
IdT Classification	IDT	Y	Y
IPC (ICM, ICS, ICA, ICI, IPCI, IPCR)	IPC	Y	Y
IPC Additional	ICA	Y	Y
IPC Additional	IPCA	Y	Y
IPC, Advanced Level Symbols for Invention	IPC.AI	Y **(4)**	N
IPC, Core Level	IPC.C	Y	N
IPC, Core Level, Invention	IPC.CI	Y	N
IPC, Reform	IPC.REF	Y	N
IPC Secondary	ICS	Y	Y
IPC Initial	ICI	Y	Y
IPC Initial	IPCI	Y	Y
IPC Main	ICM	Y	Y
IPC Reclassified	IPCR	Y	Y
Key Terms	KT	Y	N
Language	LA	Y	Y
Language of Filing	LAF	Y	Y
Number of Claims	CLMN	Y	Y
Number of Paragraphs in DETD	DETN	Y	Y
Occurrence Count of Hit Terms	OCC	N	Y
Patent Assignee	PA (CS)	Y	Y
Patent Assignee, Country	PA.CNY	Y	Y
Patent Assignee, Total	PA.T	Y	Y
Patent Assignee Normalized	PAN	Y	Y
Patent Assignee Standardized	PAS	Y	Y
Patent Country	PC	Y	Y
Patent Information Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y
Patent Number	PN (PI)	Y (default)	Y
Patent Number Group	PATS	Y	Y
Patent Number Original	PNO	Y	Y
Patent Number/Kind Code	PNK	Y **(3)**	Y
Pre-IPC8 Symbols from the ICM and first IPC8 values from	IPC.F	Y	N
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y
Priority Date First	PRDF	Y	Y
Priority Number Kind Code	PRK	Y	Y
Priority Number	PRN (PRAI)	Y	Y
Priority Number Original	PRNO	Y	Y
Priority Year	PRY	Y	Y
Priority Year First	PRYF	Y	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Related Application Country	RLC	Y	Y
Related Application Number	RLN	Y	Y
Related Application Date	RLD	Y	Y
Related Application Type	RLT	Y	N
Related Application Year	RLY	Y	Y
Related Patent Country	RLPC	Y	Y
Related Patent Number	RLPN	Y **(3)**	Y
Related Patent Date	RLPD	Y	Y
Related Patent Year	RLPY	Y	Y
Title	TIEN (TI)	Y	Y
Ultimate Owner	UO	Y	Y

SELECT, ANALYZE, and SORT Fields (cont'd)

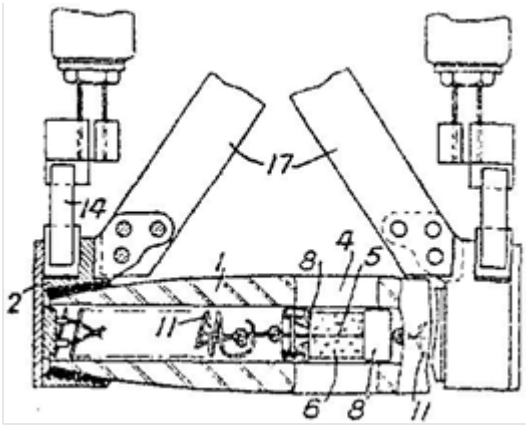
Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Ultimate Owner Standardized	UOS	Y	Y
Update Date	UP	Y	Y
Update Date Full-Text	UPTX	Y	Y

(1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
(2) Selects or analyzes application numbers with /AP appended to the terms created by SELECT.
(3) SELECT or ANALYZE HIT are not valid with this field.
(4) Appends /IPC.REF to the terms created by SELECT.

Sample Records

DISPLAY MAXG (STN format)

```
AN      1758406   GBFULL  EDP 20140615  ED 20180205 UP 20240701 EDTX 20240701
        DED 20180130 DUPD 20240625 Full-text
TIEN    Common platform for the encoder and decoder of CEPL codecs
PA      SIEMENS AG
PAS     SIEMENS
PAN     SIEMENS
LAF     English
DT      Patent; (Fulltext)
PI      GB 2004021852            D0    20041103
PIT     GBD0 PATENT APPLICATION FILED
AI      GB 2004-21852            A     20041001
PRAI    GB 2004-21852                  20041001
IPCR    G10L0019-12 [I,A]; G10L0019-14 [I,A]; G10L0019-16 [I,A]
CPC     G10L0019-04; G10L0019-12; G10L0019-16
GI
```

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AB
        Equivalent from GB2418818A
        A method and an arrangement to provide a common platform for the encoder
        and decoder of various CELP codecs used during data/speech transmission
        within a communication network, wherein common portions (1 to 4) of said
        codecs were extracted and implemented on the common platform
        communicating with the remaining portions (5 to 10) of said codecs.

DETDEN
        Equivalent from GB2418818A
        A METHOD AND AN ARRANGEMENT TO PROVIDE A COMMON PLATFORM FOR THE ENCODER
        AND DECODER OF VARIOUS CELP CODECS

        DESCRIPTION

        [DESC0003] The invention relates to a method an arrangement to provide a
        common platform for the encoder and decoder of various CELP codecs used
        during data/speech transmission within a communication networks.

        BACKROUND OF INVENTION

        [DESC0005] The presented invention particularly concerns in the
        development of the VoIP access and trunk gateways. The demands of the
        customer features are increasing, wherein resources in the gates and
        memory in used DSP, FPGA or ASIC is limited. Supporting all the features
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or increasing number of features leads - on the one hand - to more expensive ASIC, FPGA and DSP or lower port density achievement.

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SUMMARY OF INVENTION

[DESC0009] The present invention aims to overcome the above mentioned disadvantages.

[DESC0010] Said problem is solved by the features mentioned in the independent claims. Preferred embodiments of the invention are described in the dependent claims.

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Equivalent from GB2418818A

CLMEN

[CLM0001] 1. A method to provide a common platform for the encoder and decoder of various CELP codecs used during data/speech transmission within a communication networks, wherein common portions (1 to 4; 11 to 15) of said codecs were extracted and implemented on the common platform communicating with the remaining portions (5 to 10; 16 to 22) of said codecs.

[CLM0002] 2. A method as claimed in the preceding claim, wherein the codecs could be represented by AMR, by Enhanced Full Rate GSM, by G729 or by G723.

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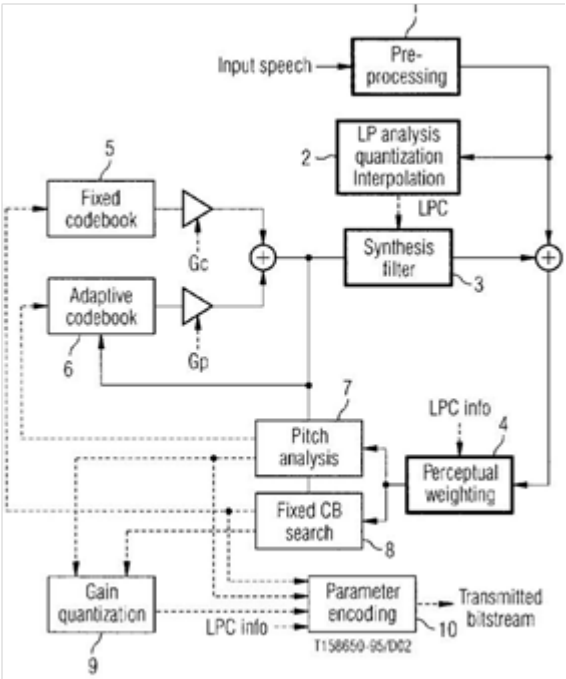
AN 1758406 GBFULL EDP 20140615 ED 20140615 UP 20240701 EDTX 20140615 UPTX 20191017
DUPD 20240625 Full-text
TIEN A method for providing a common platform for various CELP codecs
IN ARORA NITIN, DE
PA SIEMENS AG, DE
PAS SIEMENS
PAN SIEMENS
UO SIEMENS AG
UOS Siemens
LAF English
LA English
DT Patent; (Fulltext)
PI GB 2418818 A 20060405
PIT GBA PATENT SPECIFICATION [UNDER NO. 2000000] or PUBLISHED PATENT APPLICATION [FROM NO. 2000000]
AI GB 2004-21852 A 20041001
PRAI GB 2004-21852 20041001
IPCI G10L0019-04 [I,A]
IPCR G10L0019-12 [I,A]; G10L0019-14 [I,A]; G10L0019-16 [I,A]
CPC G10L0019-04; G10L0019-12; G10L0019-16

EPC G10L0019-04; G10L0019-12; G10L0019-16

GI



AB

Original
A method and an arrangement to provide a common platform for the encoder and decoder of various CELP codecs used during data/speech transmission within a communication network, wherein common portions (1 to 4) of said codecs were extracted and implemented on the common platform communicating with the remaining portions (5 to 10) of said codecs.

DETDEN

A METHOD AND AN ARRANGEMENT TO PROVIDE A COMMON PLATFORM FOR THE ENCODER AND DECODER OF VARIOUS CELP CODECS

DESCRIPTION

[DESC0003] The invention relates to a method an arrangement to provide a common platform for the encoder and decoder of various CELP codecs used during data/speech transmission within a communication networks.

BACKROUND OF INVENTION

[DESC0005] The presented invention particularly concerns in the development of the VoIP access and trunk gateways. The demands of the customer features are increasing, wherein resources in the gates and memory in used DSP, FPGA or ASIC is limited. Supporting all the features

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SUMMARY OF INVENTION

[DESC0009] The present invention aims to overcome the above mentioned disadvantages.

[DESC0010] Said problem is solved by the features mentioned in the independent claims. Preferred embodiments of the invention are described in the dependent claims.

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[DESC0030] In conclusion implementation, testing efforts and costs are reduced, the port density are diminished and a platform integrating mobile and fixed network codecs in one is provided.

CLMEN

[CLM0001] 1. A method to provide a common platform for the encoder and decoder of various CELP codecs used during data/speech transmission within a communication networks, wherein common portions (1 to 4; 11 to 15) of said codecs were extracted and implemented on the common platform communicating with the remaining portions (5 to 10; 16 to 22) of said codecs.

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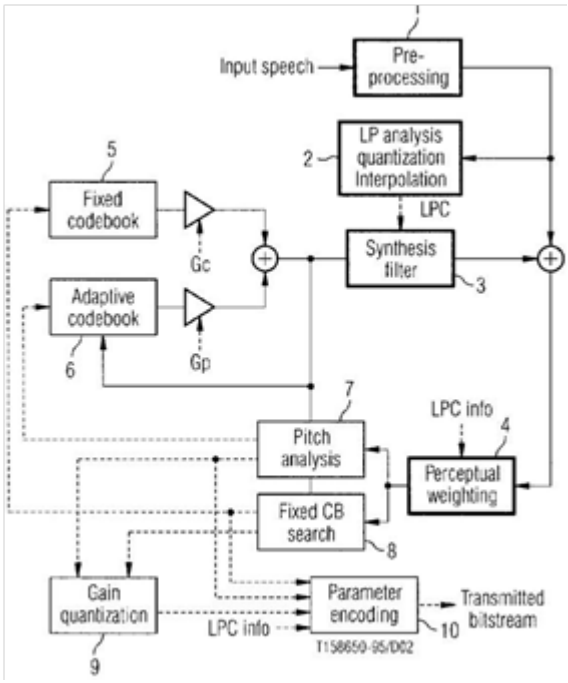
[CLM0004] 4. A platform as claimed in the preceding claim , wherein the codecs could be represented by AMR, by Enhanced Full Rate GSM, by G729 or by G723.

AN 1758406 GBFULL EDP 20140615 ED 20140615 UP 20240701 EDTX 20140615 UPTX 20191016
DUPD 20240625 Full-text
TIEN A method and an arrangement to provide a common platform for tencoder and decoder of various CELP codecs
IN ARORA NITIN, DE
PA SIEMENS AG, DE
PAS SIEMENS
PAN SIEMENS
UO SIEMENS AG
UOS Siemens
LAF English
LA English
DT Patent; (Fulltext)
PI GB 2418818 B 20070502
PIT GBB AMENDED PATENT SPECIFICATION [UNDER NO. 2000000] or PATENT SPECIFICATION [FROM NO. 2000000]
AI GB 2004-21852 A 20041001
PRAI GB 2004-21852 20041001
IPCI G10L0019-04 [I,A]
IPCR G10L0019-12 [I,A]; G10L0019-14 [I,A]; G10L0019-16 [I,A]
CPC G10L0019-04; G10L0019-12; G10L0019-16
EPC G10L0019-04; G10L0019-12; G10L0019-16

GI



AB

Equivalent from GB2418818A
A method and an arrangement to provide a common platform for the encoder and decoder of various CELP codecs used during data/speech transmission within a communication network, wherein common portions (1 to 4) of said codecs were extracted and implemented on the common platform communicating with the remaining portions (5 to 10) of said codecs.

DETDEN

[DESC0001] A method and an arrangement to provide a common platform for the encoder and decoder of various CELP codecs

DESCRIPTION

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[DESC0030] In conclusion implementation, testing efforts and costs are reduced, the port density are diminished and a platform integrating mobile and fixed network codecs in one is provided.

CLMEN

[CLM0001] 1. A method to provide a common platform for the encoder and decoder of various CELP codecs used during data/speech transmission within a communication networks, wherein common portions (1 to 4; 11 to 15) of said codecs were extracted and implemented on the common platform communicating with the remaining portions (5 to 10; 16 to 22) of said codecs.

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KT

celp codec; fixed network codec; platform integrating mobile; complex celp encoder; communication network; gate requirement; low port density; port density achievement; low bit rate codec; programming difficulty; complex chip design; adaptive code book search; enhanced full rate; celp decoder; voip access; trunk gateway; low complexity causing cost;

synthesis filter; high-pass filtering; stage example doing filtering; encoder side; pre-processing block; perceptual weighing filter; memory chip; linear prediction coefficient; high implementation; cost consuming; conclusion implementation; reflection coefficient; ip convergence

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